

VIEW Pinnacle+ Plus

Ultra-High Accuracy Dimensional Metrology System

The VIEW Pinnacle+Plus from QVI® elevates Pinnacle performance to the next level. Pinnacle+Plus features a rigid granite optical support structure and a high performance Z-axis motion assembly to produce the lowest possible uncertainty on micro-electronic parts and assemblies.

State-of-the-art linear motion control technology provides the fastest, most reliable platform available for high capacity operation in production environments ranging from clean rooms to factory floors.

- Oversized granite structure for thermal and mechanical stability
- High performance focus motion assembly
- Advanced image processing for high speed and repeatability

	X	Y	Z
Travel (mm)	250	150	50



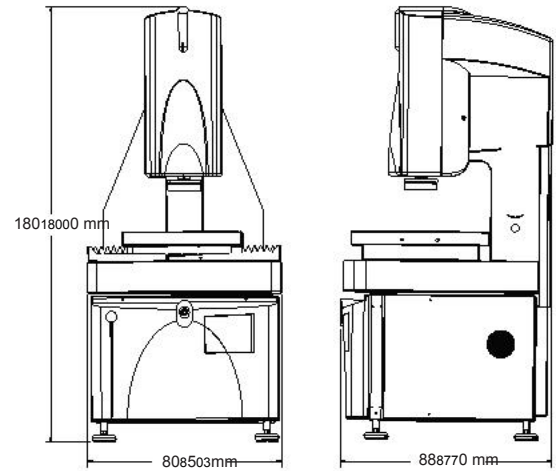
VIEW Pinnacle+ Plus

Metrology Software:

- ☐ VIEW Metrology Software (VMS)
- ☐ Optional: Element[®] metrology software
- ☐ Optional: Measure-X metrology software

Available Optional Software Modules:

- ☐ Area Multi-Focus (AMF)
- ☐ Continuous Image Capture (CIC)
- ☐ Advanced image filtering, image stitching, custom UI
- ☐ MeasureFit Plus
- ☐ SmartProfile3D GD&T evaluation software
- ☐ VMS Offline workstation software
- ☐ Digital I/O



Uncrated: 635 kg | Crated: 771 kg

	Standard		Optional	
X,Y,Z Travel (mm)	250 x 150 x 50			
X,Y,Z Scale Resolution	XY - 0.05 μm, zero expansion material Z - 0.01μm, zero expansion material			
Stage Drive System	Frictionless, high speed linear motor drives X&Y, DC servo motor Z			
Max Velocity	X,Y - 100 mm/sec / Z - 25 mm/sec			
Max Recommended Load	25 kg			
Imaging Optics	Single magnification, fixed lens optics with factory configurable back tube (1X standard) and field interchangeable front lens options (5 standard)			
Throat Clearance	Adjustable 25-150 mm			
Front Lens (Field Interchangeable)	Lens	FOV (MM)	Lens	FOV (mm)
	VIEW 5X	1.35 x 1.01	VIEW 0.8X	8.34 x 6.23
			VIEW 1X	6.46 x 4.82
			VIEW 2.5X	2.78 x 2.07
			VIEW 10X	0.69 x 0.52
			VIEW 25X	0.28 x .021
Metrology Camera	2.0 megapixel, 1/2-inch, digital, monochrome		5.0 megapixel, 1/2-inch, digital, monochrome	
Illumination	Programmable LED illumination system for coaxial through-the-lens surface light and below-the-stage backlight		Multi-color programmable ring light with motorized incidence angle control Grid autofocus system	
Sensor Options			Through-the-lens (TTL) laser Spectra Probe white light range sensor Off-axis triangulation laser	
Measurement Modes	High Speed Move And Measure (MAM)		Continuous Image Capture (CIC)	
System Controller	Quad core processor, Windows 7 Operating System and on-board networking and communication ports			
Controller Accessory Package	3-axis joystick for manual stage control, with stop/start button		Single LCD flat panel display, computer keyboard and mouse Dual LCD flat panel displays, computer keyboard and mouse	
Power Requirements	115/230 VAC, 50/60 Hz, 1-Phase, 1500W			
Rated Environment	Temperature: 18°-22° C, stable to ± 1° C Relative Humidity: 30% - 80% Vibration below 15Hz: <0.0015g			
XY Area Accuracy ^{1,2,3,4,5,6}	E ₂ : (1.0+5L/1000) μm			
Z Linear Accuracy ^{1,2,5,6}	E ₁ : (1.0+5L/1000) μm		E ₁ : (0.5+5L/1000) μm (with Spectra Probe and 10X lens)	
Notes: All specifications apply to a thermally stable machine and a certified artifact at 20°C	1. Maximum rate of temperature change: 1° C/Hour 2. Maximum vertical temperature gradient: 1° C/Meter 3. At rated velocity with evenly distributed load of 5 kg. Depending on load distribution, accuracy at higher loads may be less than standard accuracy. 4. Measured in the standard measuring plane. The standard measuring plane is defined as a plane that is within 25 mm of the worktable surface. 5. Accuracy specifications applicable to standard and optional optical configurations with 2.5X or higher objective lens magnification. 6. E ₁ Z axis linear and E ₂ XY area accuracy standards are described in QVI Publication Number 790762.			